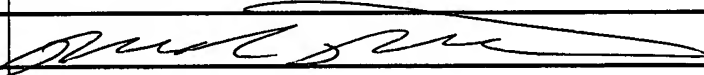


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TRANSMITTAL FORM (to be used for all correspondence after initial filing) Total Number of Pages in This Submission	Application Number	10/643,680
	Filing Date	August 18, 2003
	First Named Inventor	Brenda D. Kraus
	Art Unit	1762
	Examiner Name	Unknown
	Attorney Docket Number	MI22-2310

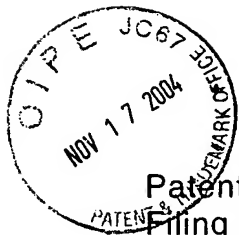
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EV 372469848



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. 10/643,680
Filing Date August 18, 2003
Inventorship Brenda D. Kraus et al.
Assignee Micron Technology, Inc.
Group Art Unit 1762
Examiner Unknown
Attorney's Docket No. MI22-2310
Title: Atomic Layer Deposition Methods of Forming Conductive Metal Nitride
Comprising Layers

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Pursuant to 1276 OG 55, August 5, 2003, no copies of cited U.S. patents or U.S. patent application publications are included, as the date of filing of this patent application occurs after June 30, 2003. No admission is made regarding whether all the submitted references are prior art.

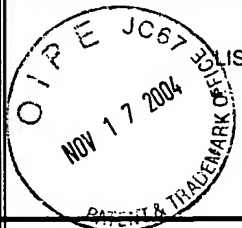
This Supplemental Information Disclosure Statement is being filed within three months of the filing date of the application or before the mailing of a first Office Action on the merits, whichever occurs last. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 11-17-04

By: 

Mark S. Matkin
Reg. No. 32,268

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2310	SERIAL NO. 10/643,680			
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT: Kraus et al.				
				FILING DATE August 18, 2003	GROUP 1762			
U.S. PATENT DOCUMENTS								
Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
	AA	6,511,539	01/2003	Raaijmakers	117	102		
	AB	6,576,053	06/2003	Kim et al.	117	89		
	AC	6,753,618	06/2004	Basceri et al.	257	915		
	AD	6,780,704	08/2004	Raaijmakers	438	239		
	AE	2001/0024387 A1	09/2001	Raaijmakers	365	200		
	AF	2002/0182320 A1	12/2002	Leskela et al.	427	250		
	AG	2003/0049931 A1	03/2003	Byun et al.	438	649		
	AH	2003/0082296 A1	05/2003	Elers et al.	427	96		
	AI	2003/0116087 A1	06/2003	Nguyen et al.	118	715		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ	WO 01/27346 A1	04/2001	WIPO				
	AK							
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AM		Juppo et al., "Use of 1,1-Dimethylhydrazine in the Atomic Layer Deposition of Transition Metal Nitride Thin Films", <i>Journal of the Electrochemical Society</i> , 147 (9), 2000, p. 3377-3381.					
	AN		H. Kim, "Atomic layer deposition of metal and nitride thin films: Current research efforts and applications for semiconductor device processing", <i>J. Vac. Sci. Technol. B</i> , Vol. 21, No. 6, Nov/Dec 2003, p. 2231-2261.					
	AO		J. W. Klaus et al., Atomic Layer Deposition of Tungsten Nitride Films Using Sequential Surface Reactions", <i>Journal of the Electrochemical Society</i> , 147 (3), 2000, p. 1175-1181.					
EXAMINER		DATE CONSIDERED						
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2310		SERIAL NO. 10/643,680	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Kraus et al.			
				FILING DATE August 18, 2003		GROUP 1762	

U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	2003/0168750 A1	09/2003	Basceri et al.	257	915	
	AB	2003/0205729 A1	11/2003	Basceri et al.	257	200	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		J. W. Elam et al., "Surface chemistry and film growth during TiN atomic layer deposition using TDMAT and NH ₃ ", Elsevier Science B.V., 12 March 2003, p. 1-12.
	AN		Juppo, "Atomic Layer Deposition of Metal and Transition Metal Nitride Thin Films and In Situ Mass Spectrometry Studies", Univ. of Helsinki, Dept. of Chemistry, 14 Dec. 2001, p. 1-65.
	AO		
EXAMINER		DATE CONSIDERED	

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